## Search Notes



Application/Control	No.

10563617

Examiner

Applicant(s)/Patent Under Reexamination
NAKAMURA, NAOHITO

1303017

Art Unit

M. Lee

2622

## **SEARCHED**

Class	Subclass	Date	Examiner
348	725, 726, 731, 732, 733	9/8/08	ml
375	329, 279, 326, 332	9/8/08	ml

SEARCH NOTES		
Search Notes	Date	Examiner
east	9/8/08	ml

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/M. Lee/ Primary Examiner.Art Unit 2622
--	--

U.S. Patent and Trademark Office Part of Paper No.: 20080908